



HiPerFET™ Power MOSFETs

N-Channel Enhancement Mode

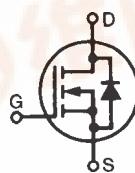
Avalanche Rated, Low Q_g
Low R_g , High dv/dt , Low t_{rr}

Preliminary Data Sheet

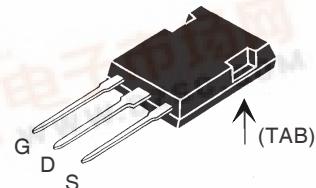
IXFR40N50Q2

V_{DSS} = 500 V
 I_{D25} = 29 A
 $R_{DS(on)}$ = 0.17 Ω

$t_{rr} \leq 250$ ns



ISOPLUS247 (IXFR)
 E153432



G = Gate D = Drain
S = Source TAB = Isolated

Symbol	Test Conditions	Maximum Ratings		
V_{DSS}	$T_J = 25^\circ\text{C}$ to 150°C	500	V	
V_{DGR}	$T_J = 25^\circ\text{C}$ to 150°C ; $R_{GS} = 1\text{ M}\Omega$	500	V	
V_{GS}	Continuous	± 30	V	
V_{GSM}	Transient	± 40	V	
I_{D25}	$T_C = 25^\circ\text{C}$	29	A	
I_{DM}	$T_C = 25^\circ\text{C}$, pulse width limited by T_{JM}	160	A	
I_{AR}	$T_C = 25^\circ\text{C}$	40	A	
E_{AR}	$T_C = 25^\circ\text{C}$	50	mJ	
E_{AS}	$T_C = 25^\circ\text{C}$	2.5	J	
dv/dt	$I_s \leq I_{DM}$, $di/dt \leq 100\text{ A}/\mu\text{s}$, $V_{DD} \leq V_{DSS}$, $T_J \leq 150^\circ\text{C}$, $R_G = 2\Omega$	20	V/ns	
P_D	$T_C = 25^\circ\text{C}$	320	W	
T_J		-55 ... +150	°C	
T_{JM}		150	°C	
T_{stg}		-55 ... +150	°C	
T_L	1.6 mm (0.063 in) from case for 10 s	300	°C	
F_c	Mounting force	22...130/5...30	N/lb.	
Weight		5	g	

Symbol	Test Conditions	Characteristic Values		
		($T_J = 25^\circ\text{C}$, unless otherwise specified)	min.	typ.
V_{DSS}	$V_{GS} = 0\text{ V}$, $I_D = 250\text{ }\mu\text{A}$	500		V
$V_{GS(th)}$	$V_{DS} = V_{GS}$, $I_D = 4\text{ mA}$	2.5		V
I_{GSS}	$V_{GS} = \pm 30\text{ V}_{DC}$, $V_{DS} = 0$			$\pm 200\text{ nA}$
I_{DSS}	$V_{DS} = V_{DSS}$ $V_{GS} = 0\text{ V}$	$T_J = 25^\circ\text{C}$ $T_J = 125^\circ\text{C}$		$25\text{ }\mu\text{A}$ 1 mA
$R_{DS(on)}$	$V_{GS} = 10\text{ V}$, $I_D = I_T$ Pulse test, $t \leq 300\text{ }\mu\text{s}$, duty cycle $d \leq 2\%$		0.17	Ω

Features

- Double metal process for low gate resistance
- International standard packages
- Epoxy meet UL 94 V-0, flammability classification
- Low $R_{DS(on)}$, low Q_g
- Avalanche energy and current rated
- Fast intrinsic rectifier

Applications

- DC-DC converters
- Switched-mode and resonant-mode power supplies, >500kHz switching
- DC choppers
- Pulse generation
- Laser drivers

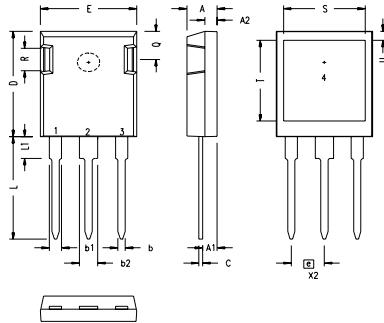
Advantages

- Easy to mount
- Space savings
- High power density

Symbol	Test Conditions	Characteristic Values		
		min.	typ.	max.
g_{fs}	$V_{DS} = 10 \text{ V}; I_D = I_T$, pulse test	15	28	S
C_{iss} C_{oss} C_{rss}	$V_{GS} = 0 \text{ V}, V_{DS} = 25 \text{ V}, f = 1 \text{ MHz}$	4200	pF	
		680	pF	
		170	pF	
$t_{d(on)}$ t_r $t_{d(off)}$ t_f	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = I_T$ $R_G = 2 \Omega$ (External),	17	ns	
		13	ns	
		42	ns	
		8	ns	
$Q_{g(on)}$ Q_{gs} Q_{gd}	$V_{GS} = 10 \text{ V}, V_{DS} = 0.5 \cdot V_{DSS}, I_D = I_T$	110	nC	
		25	nC	
		50	nC	
R_{thJC}			0.39	K/W
R_{thCK}		0.15		K/W

Source-Drain Diode
Characteristic Values
 $(T_J = 25^\circ\text{C}, \text{unless otherwise specified})$

Symbol	Test Conditions	min.	typ.	max.
I_s	$V_{GS} = 0 \text{ V}$		40	A
I_{SM}	Repetitive; pulse width limited by T_{JM}		160	A
V_{SD}	$I_F = I_s, V_{GS} = 0 \text{ V}$, Pulse test, $t \leq 300 \mu\text{s}$, duty cycle $d \leq 2 \%$		1.5	V
t_{rr} Q_{RM} I_{RM}	$I_F = 25 \text{ A}$ - $dI/dt = 100 \text{ A}/\mu\text{s}$, $V_R = 100 \text{ V}$	1 9	250 μC A	ns

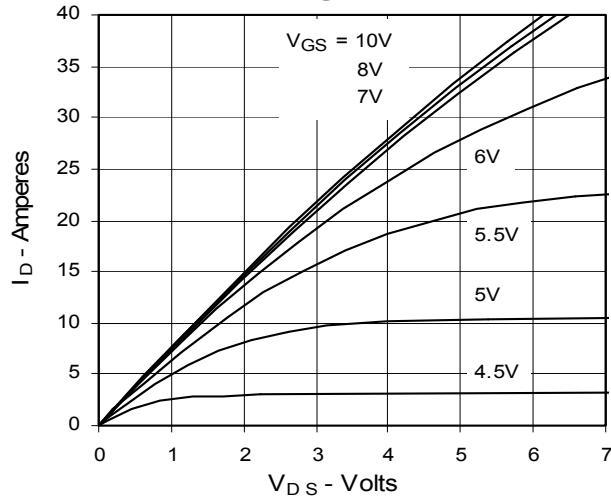
Note: Test current $I_T = 20 \text{ A}$
ISOPLUS247 Outline


SYM	INCHES		MILLIMETERS	
	MIN	MAX	MIN	MAX
A	.190	.205	4.83	5.21
A1	.090	.100	2.29	2.54
A2	.075	.085	1.91	2.16
b	.045	.055	1.14	1.40
b1	.075	.084	1.91	2.13
b2	.115	.123	2.92	3.12
C	.024	.031	0.61	0.80
D	.819	.840	20.80	21.34
E	.620	.635	15.75	16.13
e	.215 BSC		5.45 BSC	
L	.780	.800	19.81	20.32
L1	.150	.170	3.81	4.32
Q	.220	.244	5.59	6.20
R	.170	.190	4.32	4.83
S	.520	.540	13.21	13.72
T	.620	.640	15.75	16.26
U	.065	.080	1.65	2.03

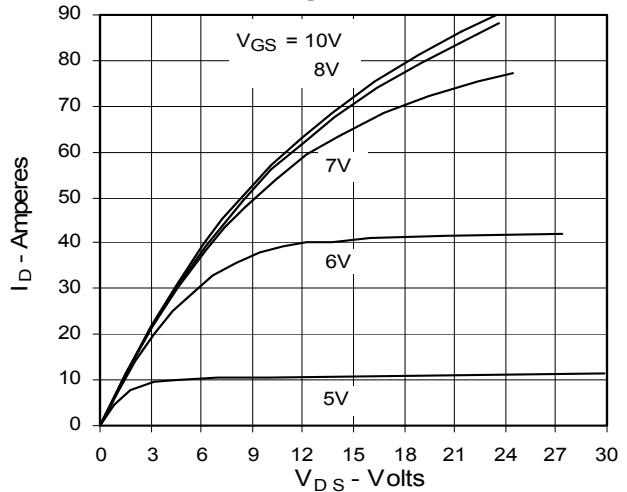
- 1 – GATE
-
- 2 – DRAIN (COLLECTOR)
-
- 3 – SOURCE (EMITTER)
-
- 4 – NO CONNECTION

NOTE: This drawing will meet all dimensions requirement of JEDEC outline TO-247AD except screw hole.

**Fig. 1. Output Characteristics
@ 25°C**



**Fig. 2. Extended Output Characteristics
@ 25°C**



**Fig. 3. Output Characteristics
@ 125°C**

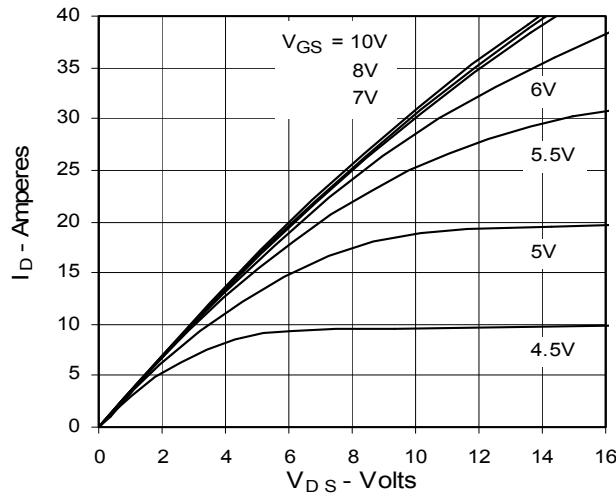
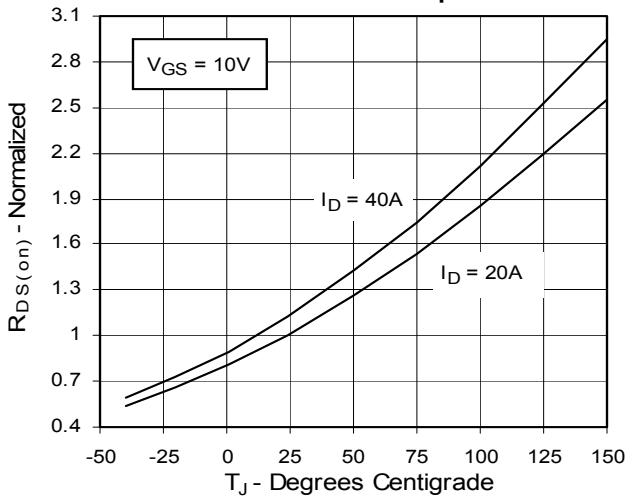


Fig. 4. $R_{DS(on)}$ Normalized to 0.5 I_{D25} Value vs. Junction Temperature



**Fig. 5. $R_{DS(on)}$ Normalized to
0.5 I_{D25} Value vs. I_D**

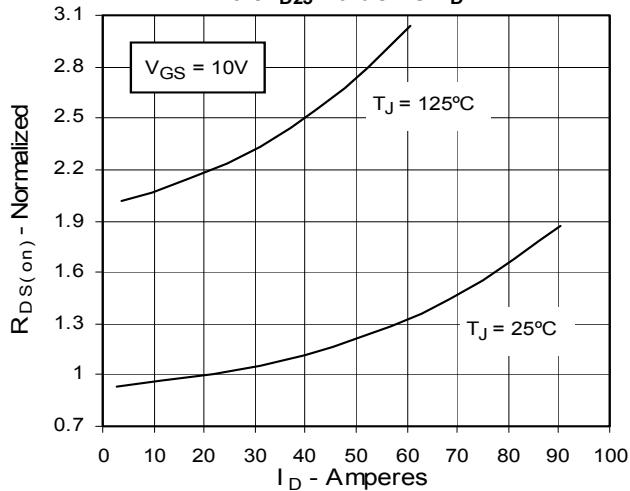


Fig. 6. Drain Current vs. Case Temperature

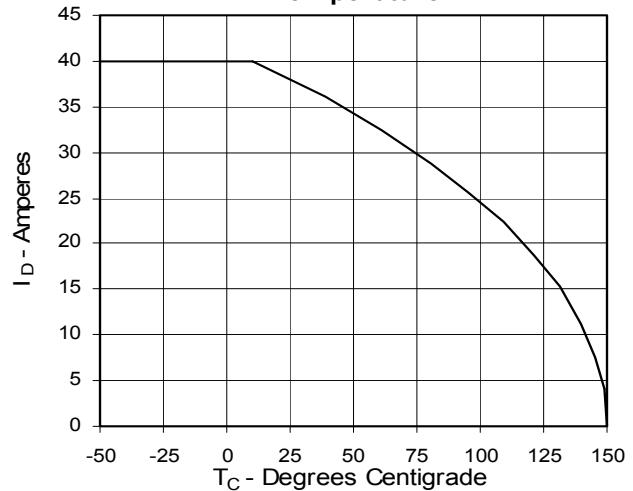
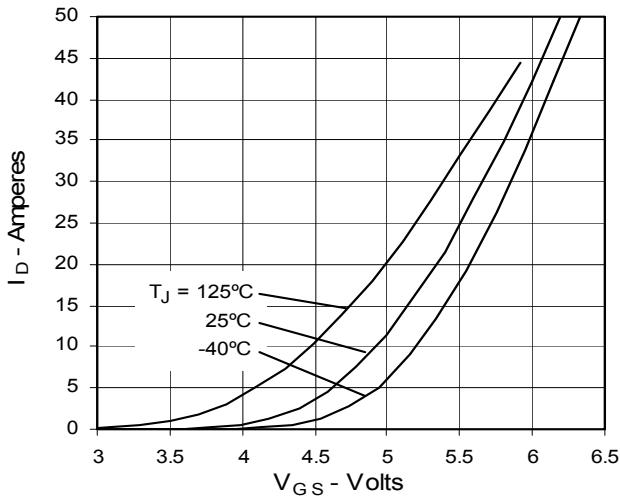
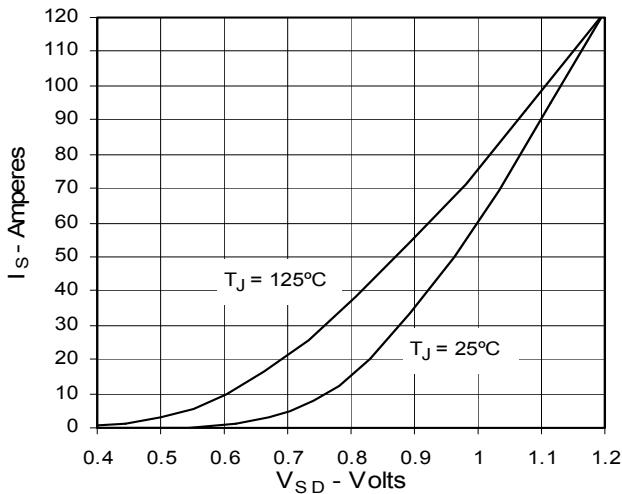
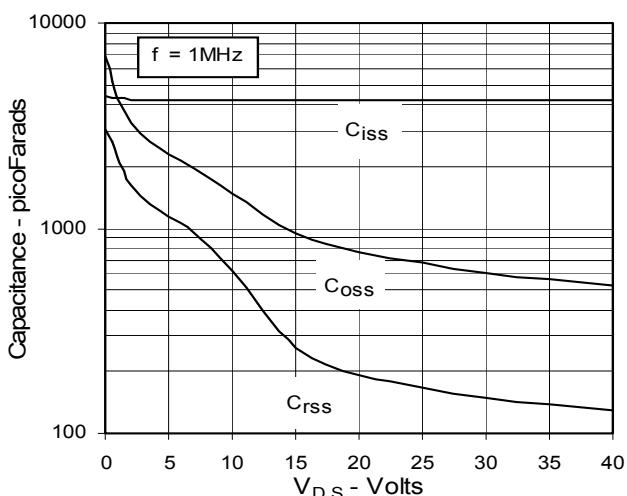
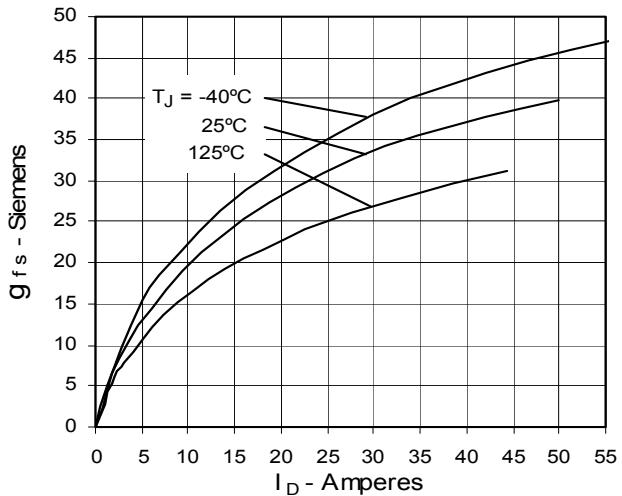
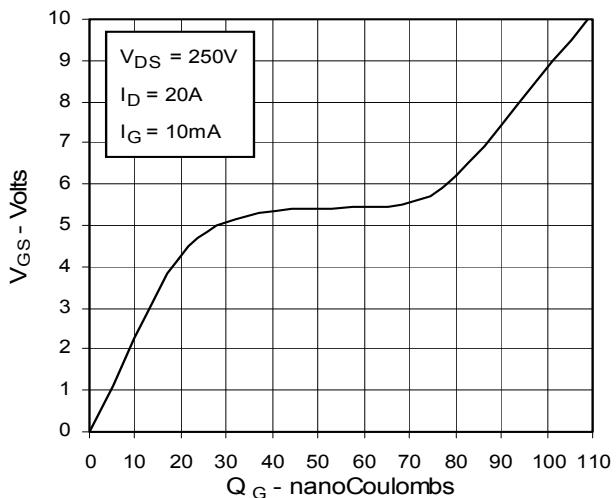
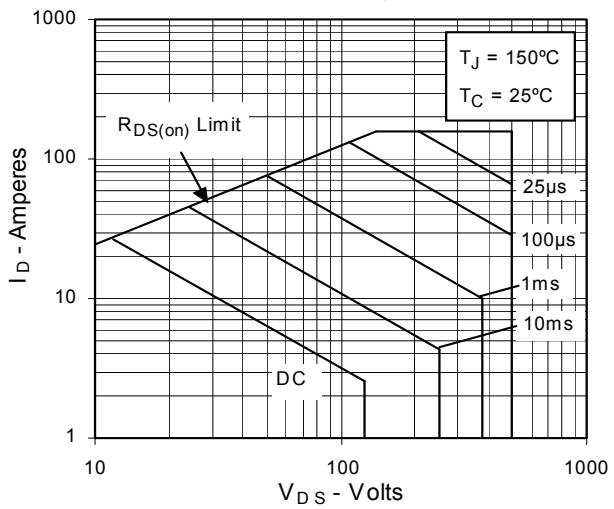


Fig. 7. Input Admittance

Fig. 9. Source Current vs. Source-To-Drain Voltage

Fig. 11. Capacitance

Fig. 8. Transconductance

Fig. 10. Gate Charge

Fig. 12. Forward-Bias Safe Operating Area


IXYS reserves the right to change limits, test conditions, and dimensions.

IXYS MOSFETs and IGBTs are covered by one or more of the following patents: 4,850,072, 4,921,844, 5,024,706, 5,062,307, 5,237,481, 5,291,005, 6,404,065P1, 6,162,665, 6,524,242, 6,582,505.

Fig. 13. Maximum Transient Thermal Resistance